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APPLICATION NO.	F	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/669,149	10/669,149 09/23/2003		Erich Strasser	56/417	2988
757	7590	10/19/2005	EXAMINER		INER
		ILSON & LION	MONBLEAU, DAVIENNE N		
P.O. BOX 1 CHICAGO,		0	ART UNIT	PAPER NUMBER	
Ź				2878	

DATE MAILED: 10/19/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	ication No. Applicant(s)				
		10/669,149	STRASSER, ERICH				
	Office Action Summary	Examiner	Art Unit				
		Davienne Monbleau	2878				
Period fo	The MAILING DATE of this communication app or Reply	pears on the cover sheet with the	correspondence address				
WHIC - Exte after - If NO - Failu Any	ORTENED STATUTORY PERIOD FOR REPLY CHEVER IS LONGER, FROM THE MAILING DASSIONS OF TIME MAILING DASSIONS OF THE MAILING THE MAI	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be to the company and will expire SIX (6) MONTHS from the course ABANDON to become ABANDON.	ON. imely filed m the mailing date of this communication. IED (35 U.S.C. § 133).				
Status							
1)	Responsive to communication(s) filed on <u>15 Same</u>	entember 2005					
	_	action is non-final.					
3)	,—····································						
-,-	closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.						
Dispositi	on of Claims						
4)⊠	Claim(s) 1-19 is/are pending in the application.						
	4a) Of the above claim(s) is/are withdrawn from consideration.						
	Claim(s) is/are allowed.						
· —	Claim(s) <u>1-19</u> is/are rejected.						
7)	•						
·	Claim(s) are subject to restriction and/or	r election requirement					
	are subject to restriction and/or	election requirement.					
Applicati	on Papers						
9)☐ The specification is objected to by the Examiner.							
10)⊠ The drawing(s) filed on <u>23 September 2003</u> is/are: a)⊠ accepted or b)□ objected to by the Examiner.							
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).							
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).							
11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.							
Priority u	nder 35 U.S.C. § 119						
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 							
\ttachment	(a)						
_	e of References Cited (PTO-892)	4) Interview Summary	v (PTO-413)				
2) 🔲 Notice	of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s)/Mail D	Date				
	nation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) No(s)/Mail Date	5)	Patent Application (PTO-152)				

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DETAILED ACTION

Response to Amendment

The amendment filed on 9/15/05 has been entered. Claim 1 has been amended. New Clams 18 and 19 have been added. Claims 1-19 are pending.

Claim Objections

Regarding Claim 19, the phrase "wherein said detector arrangement comprises a plurality of detector elements" is not further limiting because Claim 1 already recites "an arrangement of detector elements."

Claim 19, line 2: "each on" should be changed to -- each one -- .

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 1, 8, 10-12, 18, and 19 are rejected under 35 U.S.C. 102(e) as being anticipated by Mayer et al. (U.S. 6,472,658).

The applied reference has a common assignee with the instant application. Based upon the earlier effective U.S. filing date of the reference, it constitutes prior art under 35 U.S.C. 102(e). This rejection under 35 U.S.C. 102(e) might be overcome either by a showing under 37 CFR 1.132 that any invention disclosed but not claimed in the reference was derived from the

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inventor of this application and is thus not the invention "by another," or by an appropriate showing under 37 CFR 1.131.

Regarding Claim 1, *Mayer* discloses in Figures 1 and 6 a position measuring instrument comprising a periodic incremental graduation (2) comprising a plurality of graduation periods within one measurement range, a reference marking (R) disposed within said measurement range and integrated with said incremental graduation (2), and an arrangement of detector elements (5, 6) over at least a length of said measurement range for generating a plurality of periodic scanning signals (column 5 lines 5-20) of which at least one is modified locally by said reference marking (R). *Mayer* discloses (column 7, lines 61-65) determining an absolute position of said reference marking within said length of said measurement range as a function of said detected at least one scanning signal. Thus, it is inherent that there is an evaluation device that receives said scanning signals and detects at least one scanning signal, modified by said reference marking, from said plurality of scanning signals in order to determine that position.

Regarding Claim 12, *Mayer* discloses in Figures 1 and 6 a method for position measurement comprising scanning (column 5 lines 5-20) a plurality of graduation periods of one incremental graduation (2) by a detector arrangement extending over a length of one measurement range, a reference marking (R) being integrated with one of said graduation periods, and generating a plurality of periodic scanning signals, of which at least one is locally modified by said reference marking (R), detecting (5, 6) said at least one scanning signal, modified by said reference marking (R), from among said plurality of periodic scanning signals, and determining an absolute position of said reference marking within said length of said measurement range as a function of said scanning signal detected (column 7 lines 61-65).

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Regarding Claim 8, *Mayer* discloses in Figure 6, that said reference marking (R) is a variation of an interstice in a series of equally spaced markings which forms said incremental graduation (2).

Regarding Claim 10, *Mayer* discloses in Figure 1 that parallel to and next to said incremental graduation (2), an absolute code (1) for absolute position measurement is disposed at measurement increments in accordance with said length of one measurement range.

Regarding Claim 11, *Mayer* discloses that said absolute code (1) is a single-track sequential code with successive code elements.

Regarding Claims 18 and 19, *Mayer* discloses in Figure 1 that the detector arrangement comprises a plurality of detector elements (5, 6), wherein each one of said detector elements (5, 6) is assigned to its own corresponding location within said length of said measurement range and said absolute position of said reference marking determined by said evaluation device is one of said corresponding locations of said detector elements within said length of said measurement range.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 2-7, 9, and 13-17 are rejected under 35 U.S.C. 103(a) as being obvious over Mayer in view of Keong (U.S. 2005/0006571).

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The applied reference has a common assignee with the instant application. Based upon the earlier effective U.S. filing date of the reference, it constitutes prior art only under 35 U.S.C. 102(e). This rejection under 35 U.S.C. 103(a) might be overcome by: (1) a showing under 37 CFR 1.132 that any invention disclosed but not claimed in the reference was derived from the inventor of this application and is thus not an invention "by another"; (2) a showing of a date of invention for the claimed subject matter of the application which corresponds to subject matter disclosed but not claimed in the reference, prior to the effective U.S. filing date of the reference under 37 CFR 1.131; or (3) an oath or declaration under 37 CFR 1.130 stating that the application and reference are currently owned by the same party and that the inventor named in the application is the prior inventor under 35 U.S.C. 104, together with a terminal disclaimer in accordance with 37 CFR 1.321(c). This rejection might also be overcome by showing that the reference is disqualified under 35 U.S.C. 103(c) as prior art in a rejection under 35 U.S.C. 103(a). See MPEP § 706.02(l)(1) and § 706.02(l)(2).

Regarding Claim 2, Mayer teaches in Figures 1 and 6 that within said measurement range, N graduation periods are disposed, where N>1 and is an integer. Mayer teaches using plurality of detectors, but does not teach that said arrangement of detector elements over said length of said measurement range forms N groups, and each of said N groups of detector elements extends over said length of one graduation period, and within each of said N groups, a plurality of detector elements are spaced apart from one another by a fraction of one graduation period, so that, within one of said N groups, a plurality of periodic scanning signals phase-offset from one another are generated. Keong teaches in Figure 9 a linear position encoder comprising an incremental graduation (150) with a measurement range and at least two groups of detectors,

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wherein each detector group extends over one graduation period and the detector elements within each detector group are spaced apart from one another by a fraction of one graduation period, so that, a plurality of periodic scanning signals phase-offset from one another are generated. Keong does not teach that that there are N detector groups. It would have been obvious, however, to one of ordinary skill in the art at the time of the invention to use a particular number of detector groups and detector elements within each detector group in Mayer, to improve the resolution and position detection accuracy of the device. (See *Keong* paragraph [0004]).

Regarding Claims 3-5 and 13-17, methods for determining the absolute position of an object by evaluating the detected phase signals from the encoder are well known and involve standard data analysis techniques. This includes comparing the detected phase signals from the scanned beams and interpolating the absolute position from the detected signals.

Regarding Claim 6, Mayer teaches in Figure 6 that said reference marker (R) is integrated into the incremental graduation (2), which is a phase grating. Thus, there is going to be interference in periodicity at the reference marker (R) location within the incremental graduation. Using a particular size reference marker (R) within said incremental graduation (2) depends on the desired characteristics of the position encoder. Furthermore, methods for determining the absolute position of an object by evaluating detected phase signals from the encoder are well known and involve standard data analysis techniques and may include comparing the detected phase signals from the scanned beams.

Regarding Claim 7, methods for determining the absolute position of an object by evaluating the detected phase signals from the encoder are well known and involve standard data

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analysis techniques. This includes comparing the detected phase signals from the scanned beams and interpolating the absolute position from the detected signals.

Regarding Claim 9, *Mayer* teaches in Figure that said reference marker (R) has a few components but does not teach a second reference marker. It would have been obvious, however, to one of ordinary skill in the art at the time of the invention to use a second reference marker in *Mayer* to more accurately determine the absolute position of the device. (See *Keong* paragraph [0004] stating that the ultimate resolution is determined by the stripe pattern, which would include reference markers).

Response to Arguments

Applicant's arguments filed 9/15/05 have been fully considered but they are not persuasive. Applicant makes the following arguments:

- A. Mayer does not teach an evaluation device that receives signals from an arrangement of detector elements.
- B. Mayer does not detect a signal modified by a reference marker from a plurality of scanning signals.
- C. The absolute position in *Mayer* is not determined as a function of a detected scanning signal modified by a reference marking.

Regarding argument A, Examiner agrees that elements 5 and 6 are photodetectors but does not find Applicant's argument persuasive because *Mayer* inherently includes an evaluation device that receives the signals in order to determine the position. This evaluation device may either be integral with or external to the detectors (5, 6).

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Regarding argument B, Applicant's argument is not persuasive because the reference marker (R) modulates the scanned beams (column 5 lines 5-39.) Thus, the position is determined by a signal modified by a reference marker (R). (See also column 7, lines 56-65.)

Regarding argument C, since argument is not persuasive, it follows that *Mayer* does discloses determining a position as a function of a detected scanning signal modified by a reference marking.

Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Davienne Monbleau whose telephone number is 571-272-1945. The examiner can normally be reached on Mon-Fri 9:00 am to 5:00 pm.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Dave Porta can be reached on 571-272-2444. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

DNM

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